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Application/Control No.	Applicant(s)/Patent under Reexamination
10/735,796	HADAYIA ET AL.
Examiner	Art Unit
LEE D. WILSON	3723

SEARCHED			
Class	Subclass	Date	Examiner
29	256	4/24/2007	LW [.]
	255-268		
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	278		
254	102		
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